

## **Dr. Earll M. Murman**

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Prof. Murman served as Co-Director of the Lean Aerospace Initiative from 1995-2002 and as Head of MIT's Department of Aeronautics and Astronautics from 1990-1996. In addition to his 26 years in academia, his career includes 4 years at the Boeing Company, 6 years with Flow Research Co., and 3 years at NASA's Ames Research Center.

Dr. Murman's professional interests span system engineering, product development, Lean Six Sigma, aerodynamics, computational fluid dynamics, healthcare, and engineering education. He has published over 100 journal articles and technical papers in these fields. Dr. Murman is the lead author of the book *Lean Enterprise Value: Insights from MIT's Lean Aerospace Initiative* published by Palgrave in March 2002. *Lean Enterprise Value*, a definitive account of the past and future implementation of lean principles and practices in the aerospace domain, received the 2003 Best Engineering Sciences Book Award from the International Astronautical Academy. He is a co-recipient of The 2011 Shingo Research and Professional Publication Award and the 2010 International Council of System Engineering Best Product Award for "Lean Enablers for Systems Engineering."

Dr. Murman graduated summa cum laude in Aeronautical Engineering from Princeton University in 1963 and received his PhD in Aerospace Engineering from Princeton in 1967. He is a member of the U.S. National Academy of Engineering, a Foreign Member of the Royal Swedish Academy of Engineering Sciences, President of the Washington State Academy of Sciences, an Honorary Fellow of the American Institute of Aeronautics and Astronautics, and member of INCOSE and the Academy for Healthcare Improvement.

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